

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
CHAN, HARK C.

Examiner

SARGON N. NANO

Art Unit

2457

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,257,106	08-2007	Chen et al.	370/338
*	C	US-7,424,024	09-2008	Chen et al.	370/401
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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